IEC QUALITY ASSESSMENT SYSTEM (IECQ)
covering Electronic Components,
Assemblies, Related Materials and Processes
For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Conformity

Approved Process

IECQ Certificate No.: IECQ-L ULTW 09.0027

CB Certificate No.: T1141

Schedule Number: IECQ-L ULTW 09.0027-S **Rev No.:** 1 **Revision Date:** 2018/10/04 **Page** 1 **of** 1

Appendix-1 (T1141)
Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
Electrical Analysis (IV-curve tracer, TDR, Probing test, Electric meter, Isolation test, Open/short test, Auto curve tracer, Network analyzer, Module product analysis test, Power supply test, Thermal emission test, OBIRCH test, LCR meter, Oscilloscope)	AFOP-02, AFOP-03, AFOP-04, AFOP-05, AFOP-16, AFOP-17, AFOP-21, AFOP-22, AFOP-24, AFOP-26, AFOP-29, AFOP-30, AFQP-34, AFOP-37, or per customer requirements.
Physical Analysis (Chemical etch test, High/Low-power microscope, Laser de-cap, Chemical de-cap, Molding /Grinding /Polishing /Cutting test, PECS test, SAT test, 2D/3D CT X-ray, CP test, RIE, Ion milling, PFIB, X-RADIA CT X-ray, SEM&EDX, Laser marking , IR microscope)	AFOP-01, AFOP-06, AFOP-10, AFOP-12, AFOP-13, AFOP-15, AFOP-18, AFOP-19, AFOP-20, AFOP-23, AFOP-25, AFOP-27, AFOP-28, AFOP-31, AFOP-35, AFOP-36, or per customer requirements.

Technical Reviewer of DQS ______________ Date: 10/4/2018

DQS-Group - DQS Taiwan Inc., Feng Yuan Dist., Taichung City, Taiwan